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ion probe microanalysis (IPMA)

Any technique in which the specimen is bombarded by a focused beam of (primary) ions (diameter less than 10 μm) and the (secondary) ions ejected from the specimen are detected after passage through a mass spectrometer.

Source:

PAC, 1983, *55*, 2023 *(Nomenclature, symbols and units recommended for in situ microanalysis (Provisional))* on page 2025
PAC, 1979, *51*, 2243 *(General aspects of trace analytical methods - IV. Recommendations for nomenclature, standard procedures and reporting of experimental data for surface analysis techniques)* on page 2246